

FORM PTO-892 (REV. 2-92)			U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	SERIAL NO.	GROUP ART UNIT	ATTACHMENT TO PAPER NUMBER	4
NOTICE OF REFERENCES CITED			08/111,298 APPLICANT(S)	2500			
U.S. PATENT DOCUMENTS							
*	DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE	
A	4 0 3 5 0 8 5	7.77	SEINER	350	448		
B	4 4 5 5 0 9 0	6.84	ROBERTS	350	448		
C	4 5 7 5 2 5 2	3.86	AKIYAMA	250	228		
D	4 8 9 9 0 5 5	2.90	ADAMS	250	372	5/12/88	
E	5 1 0 1 1 1 1	3.92	Kondo	250	560	6/7/690	
F	5 1 2 0 9 6 6	6.92	Kondo	250	372	2/16/91	
G							
H							
I							
J							
K							
FOREIGN PATENT DOCUMENTS							
*	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUB-CLASS	PERTINENT SHTS. / PP. DWG. SPEC.
L	6 4 1 3 4 3 8	1.89	JAPAN	MINAGAWA et al	250	372	
M							
N							
O							
P							
Q							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
R	"Measurement						
S	BARKLEY, JOHN R. "MEASUREMENT AND ANALYSIS OF REFERENCE SPECTRA OF SiP ₂ " Applied Optics Vol. 11 No. 9, (Sept 1972) p. 1928 - 1935.						
T							
U							
EXAMINER		DATE					
D. DeA		22 Dec 1993					
* A copy of this reference is not being furnished with this office action. (See Manual of Patent Examining Procedure, section 707.05 (a).)							